## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

First Named

Inventor:

Kyekyoon Kim

Serial No.:

10/728,190

Group Art Unit No. 1616

Filing Date:

December 4, 2003

Examiner To Be Assigned

Title:

**MICROPARTICLES** 

## INFORMATION DISCLOSURE STATEMENT

M.S. – Amendment Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

## Dear Sir:

In accordance with the provisions of 37 C.F.R. § 1.56, Applicants request that citation and examination of the references identified on the attached Form PTO-1449, required copies of which are enclosed herewith in accordance with 37 C.F.R. §1.98, be made during the course of examination of the above-referenced application for United States Letters Patent.

Respectfully submitted,

Evan Law Group LLC 566 West Adams Suite 350 Chicago, Illinois 60661 (312) 876-1400 Paul E. Rauch, Ph.D., Registration No. 38,591

Form PTO-1449 (Rev. 8-88)	Attorney Docket No. ILL01-002-US	Serial No. 10/728,190
	First Named Inventor Kyekyoon Kim	1
INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)	Filing Date: December 4, 2003	Group: 1616

U.S. PATENT DOCUMENTS							
Examiner Initials*		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	Z1	5,344,676	09/1994	Kim, et al.			
	Z2	2002/0054912	05/2002	Kim, et al.			

			FOREIGN	PATENT DOCUMENTS				
Examiner							Translation	
Initials*		Document Number	Date	Country	Class	Subclass	Yes	No
	Y1	WO 02/13786	02/2002	wo				

Examiner		OTHER ITEMS - NON PATENT LITERATURE DOCUMENTS
Initials*		Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages
	X1	Berkland, C., et al., "Fabrication of PLG microspheres with precisely controlled and monodisperse size distributions"., Journal of Controlled Release, vol. 73, pp. 59-74, (2001).
	X2	International Search Report dated March 16, 2006 for corresponding PCT application number PCT/US2004/040195.
	Х3	You, JO., et al., "Preparation of regular sized Ca-alginate microspheres using membrane emulsification method"., Journal of Microencapsulation, vol. 18, no. 4, pp. 521-532, (2001).

F	
Examiner	Date Considered